

# DRD3 collaboration meeting

Simulating solid state detectors with Garfield++

Djunes Janssens and Heinrich Schindler

On behalf of all Garfield++ developers

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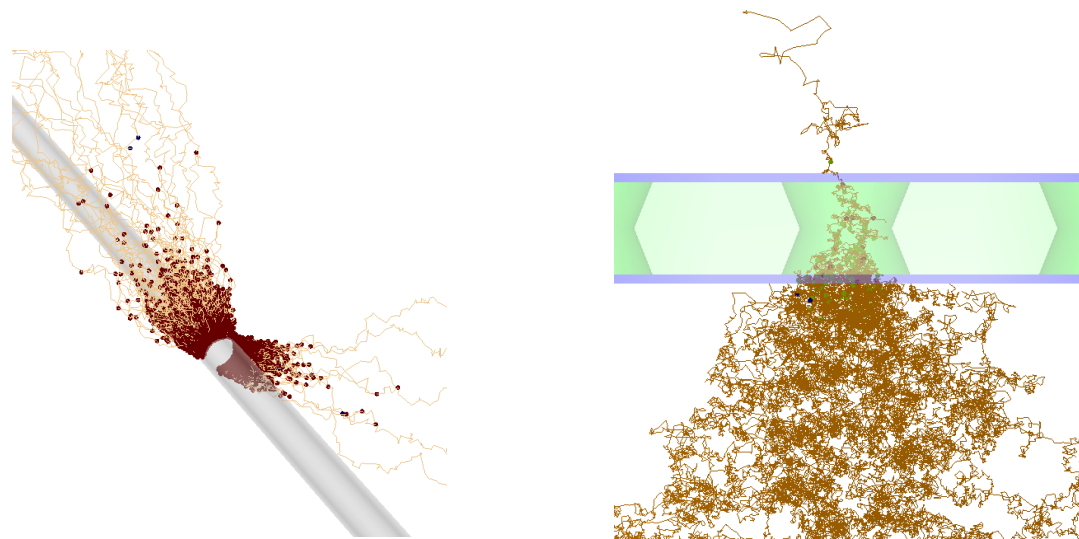
June 20<sup>th</sup>, 2024



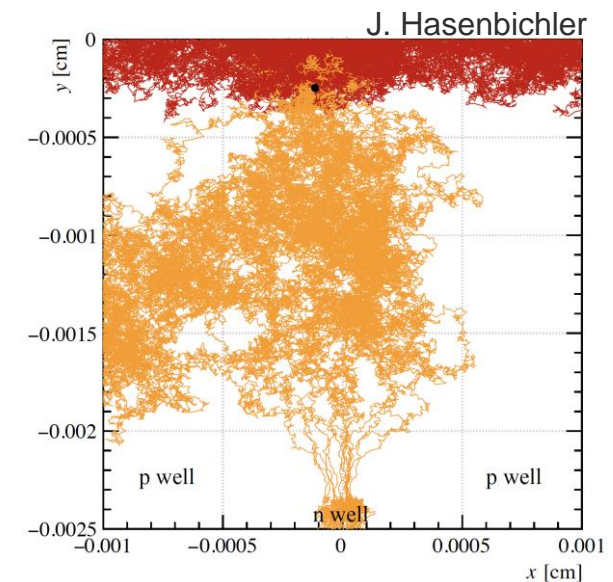
# Introduction

Garfield++ is an open-source Monte Carlo toolkit developed for detailed simulations of particle detectors, utilizing ionization measurements in both gases and semiconductors.

It builds upon the foundation of the widely-used Fortran program Garfield (R. Veenhof), which has been extensively used for simulating gas-based detectors.



Microscopic simulation of electron avalanches in a GEM (left) and around a wire (right).



Drift lines from a Monolithic silicon sensors.

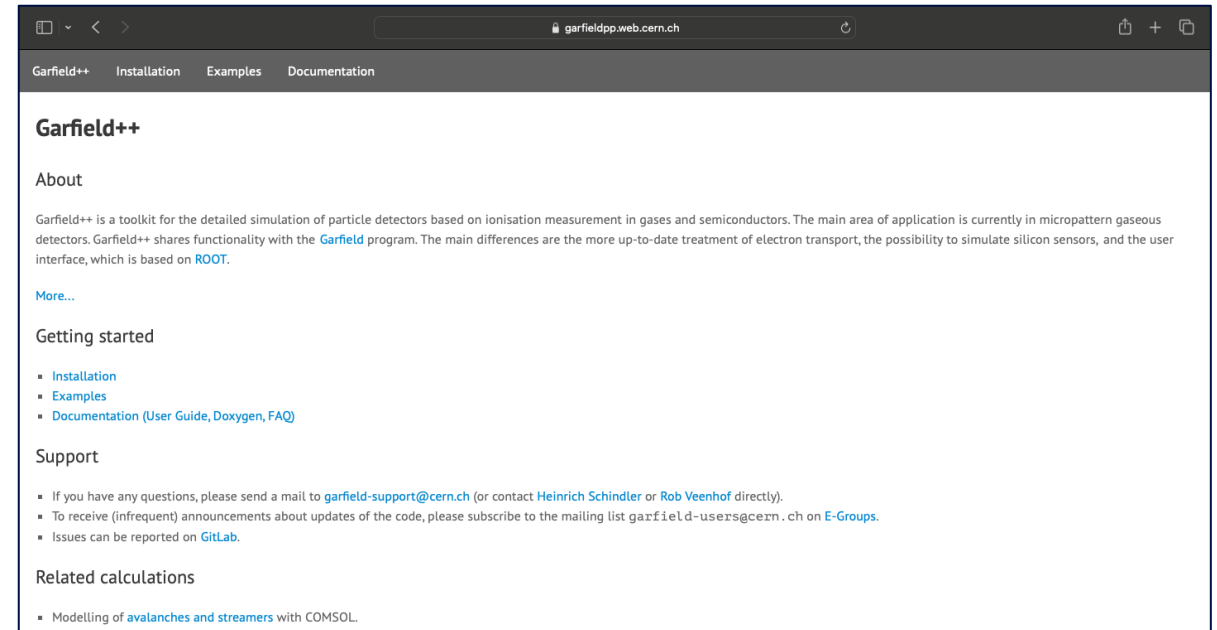
# Introduction

The further development of Garfield++ is a community-driven undertaking, with new contributions to the main branch being reviewed by a small group of “maintainers”.

We will provide a brief overview of the simulation capabilities of this toolkit by covering some key examples.

## Outline:

- Primary ionization
- Charge transport
- Signal induction
- Charge amplification (LGAD and SPAD)
- Time-dependent weighting potentials
- Summary



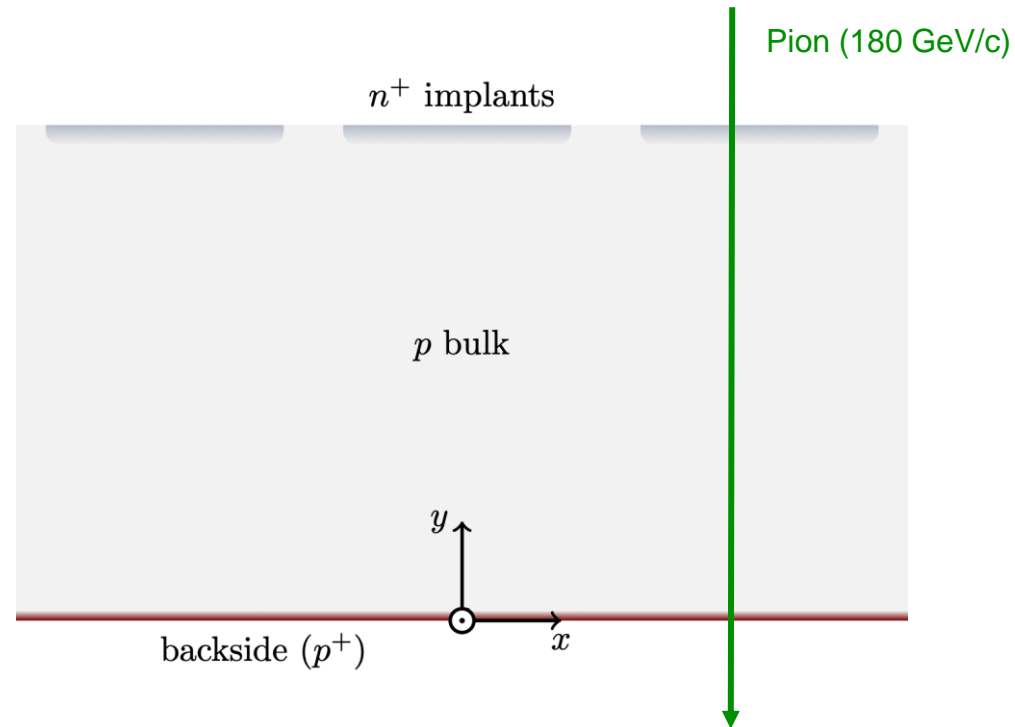
Garfield++ webpage: <https://garfieldpp.web.cern.ch/garfieldpp/>



# Primary ionization

The primary ionization pattern resulting from the energy transfer from the incident particle to the sensitive medium can be simulated using Garfield++ for:

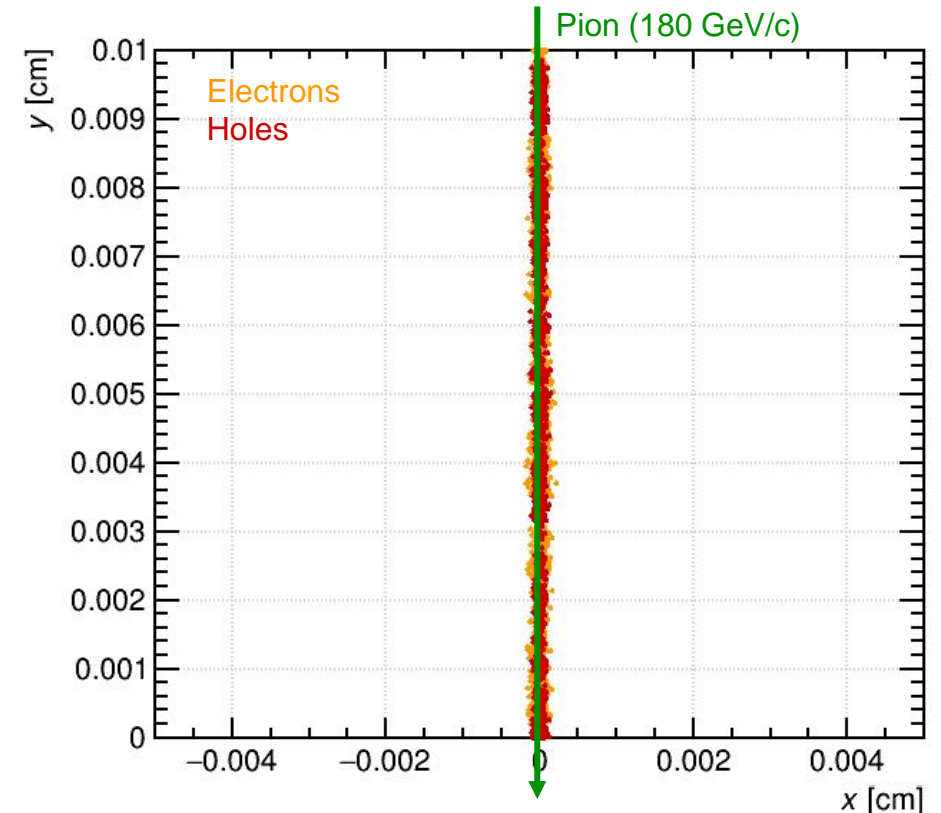
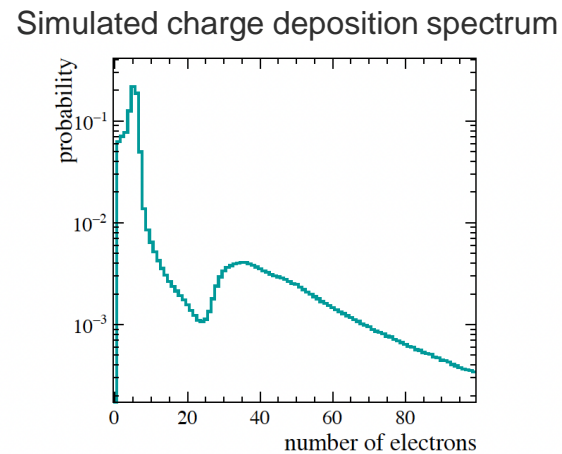
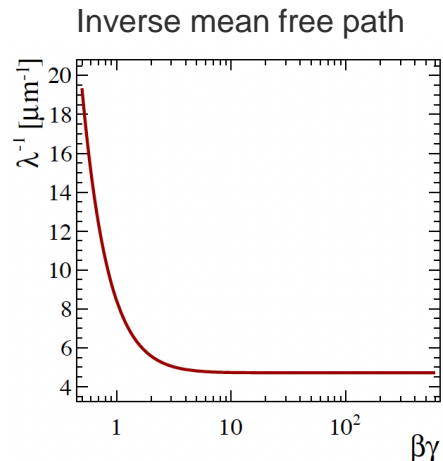
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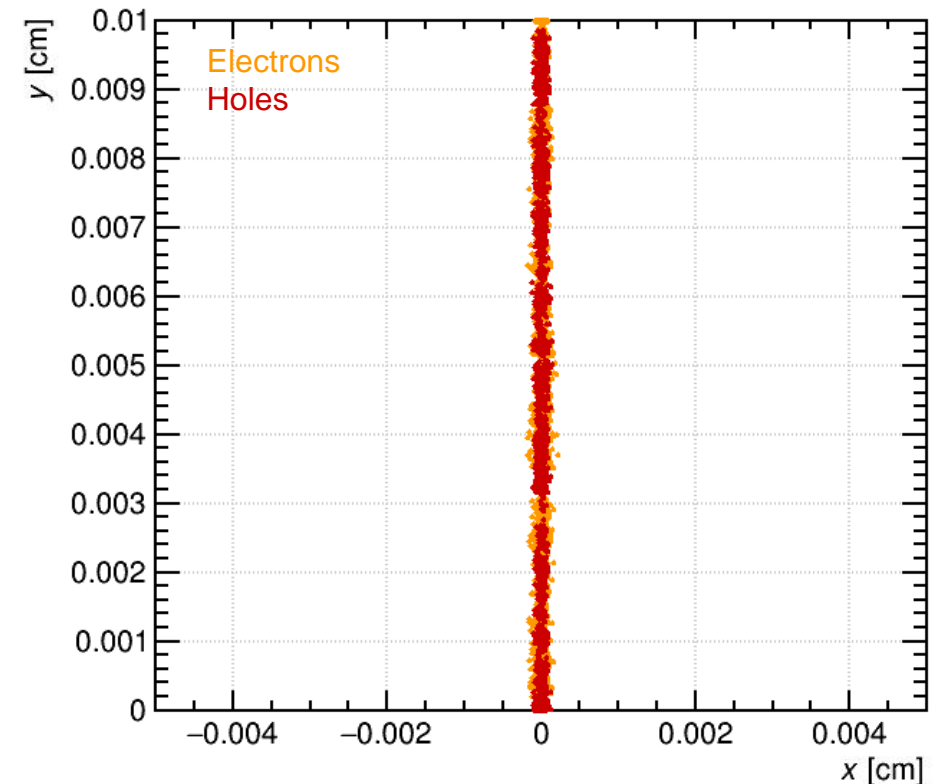
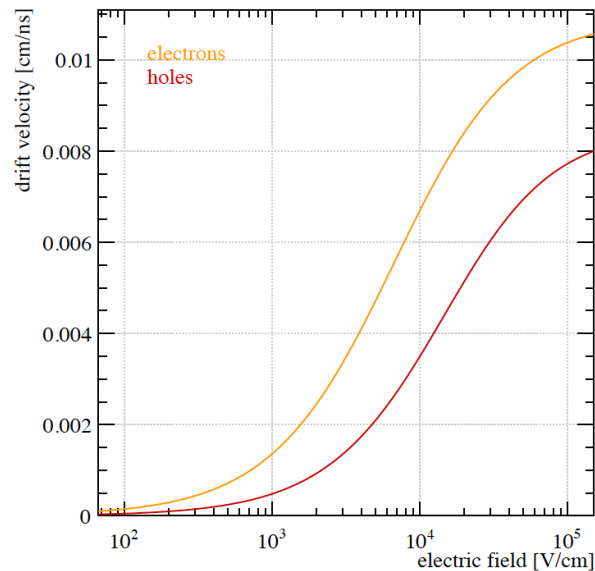
- **Charged relativistic** particle using the interface with Heed, based on an extended version of the PAI model.
- **X-Ray** photoabsorption using the interface with Heed.
- **Ion track** using simulation imported results from Srim or Trim.
- **Other** from a possible interface with GEANT4



# Charge transport

A typical approach for silicon is to simulate the drift lines of individual electrons and holes using a Monte Carlo technique based on macroscopic transport parameters.

- Canali high-field mobility model (drift velocity silicon)
- Other models and materials other than silicon are also available
- (Synopsys Sentaurus) TCAD transport data can be imported

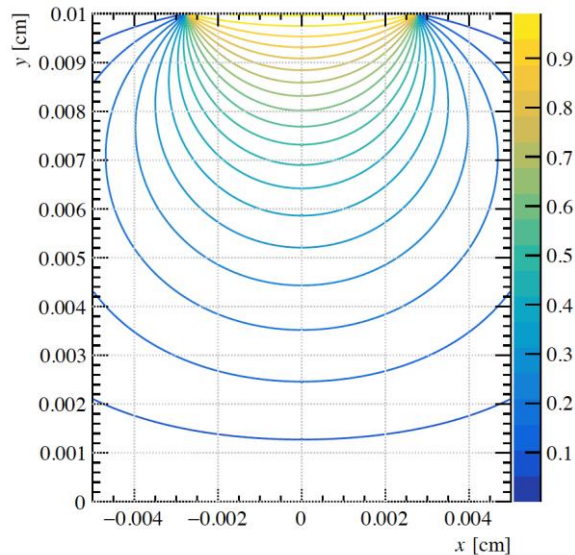


# Signal induction

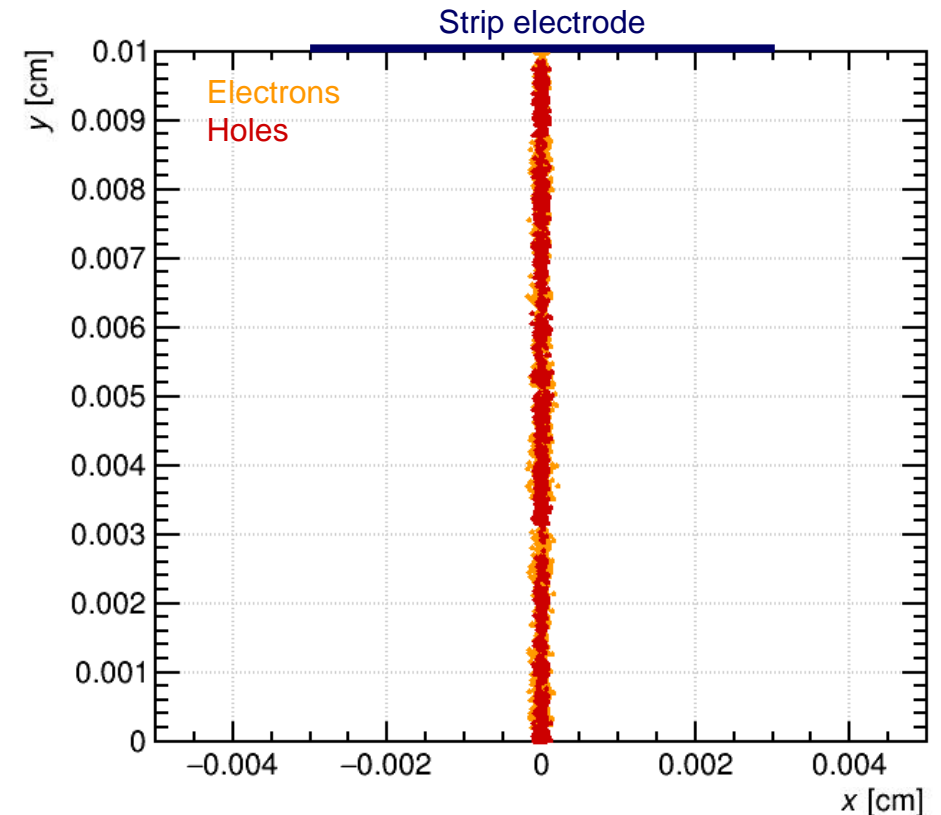
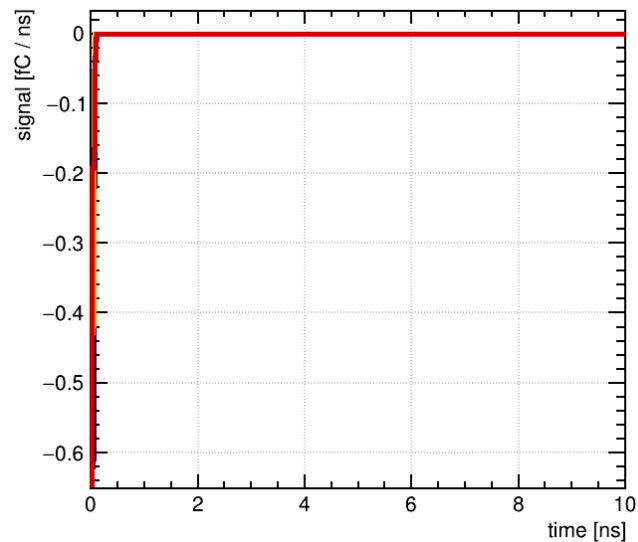
The Ramo-Shockley theorem is used to induce signals on readout electrodes by charge movement. Weighting potentials are calculated using built-in analytical solutions or numerically via FEM solvers.

$$I_i(t) = -\frac{q}{V_w} \mathbf{E}_i(\mathbf{x}_q(t)) \cdot \dot{\mathbf{x}}_q(t), \quad \mathbf{E}_i(\mathbf{x}) = -\nabla \Psi_i(\mathbf{x})$$

Weighting potential  $\psi_i(x)$  of strip electrode



Signal  $I_i(t)$  induced on strip electrode

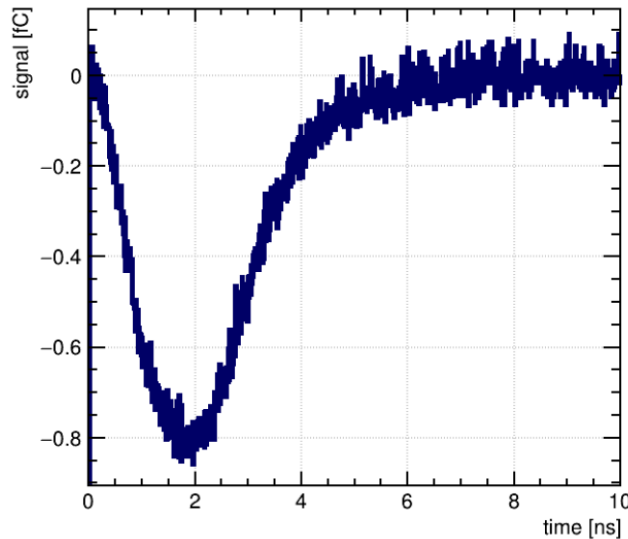


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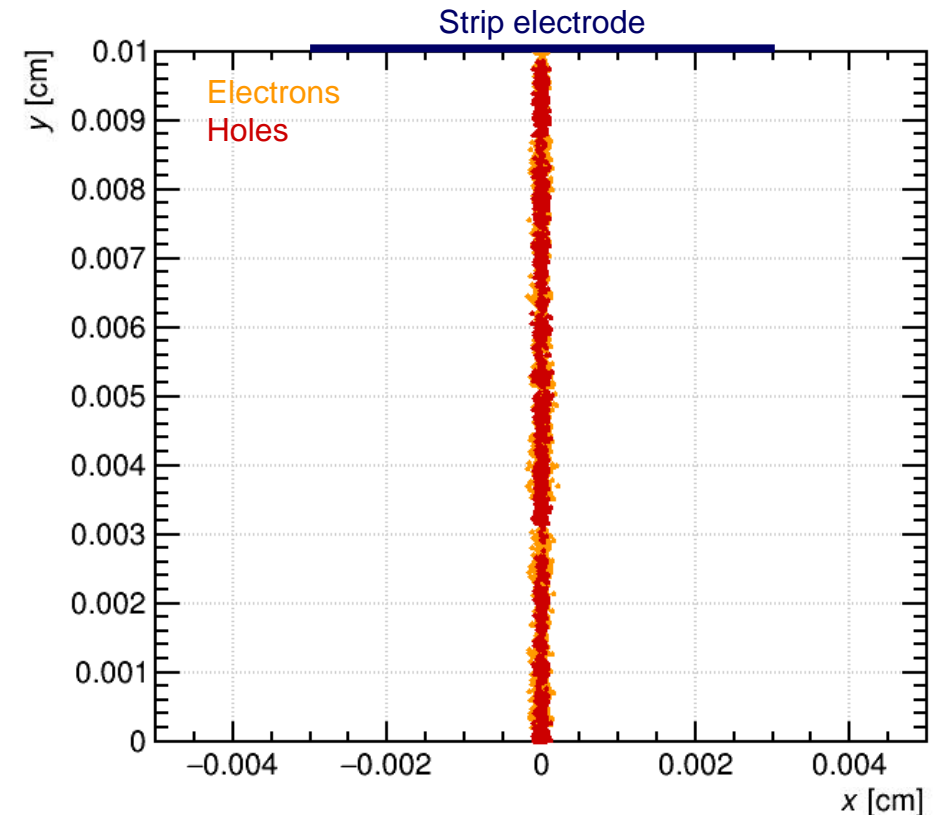
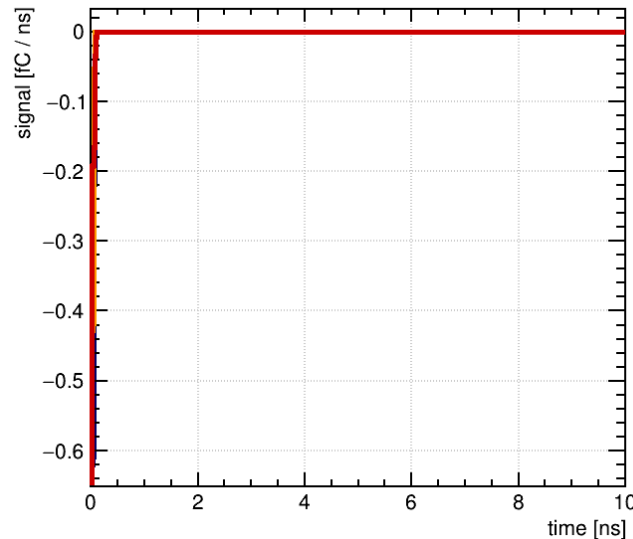
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Noisy signal after front-end



Signal  $I_i(t)$  induced on strip electrode



S. Ramo, PROC. IRE 27, 584 (1939).  
W. Shockley, Journal of Applied Physics. 9 (10): 635 (1938).

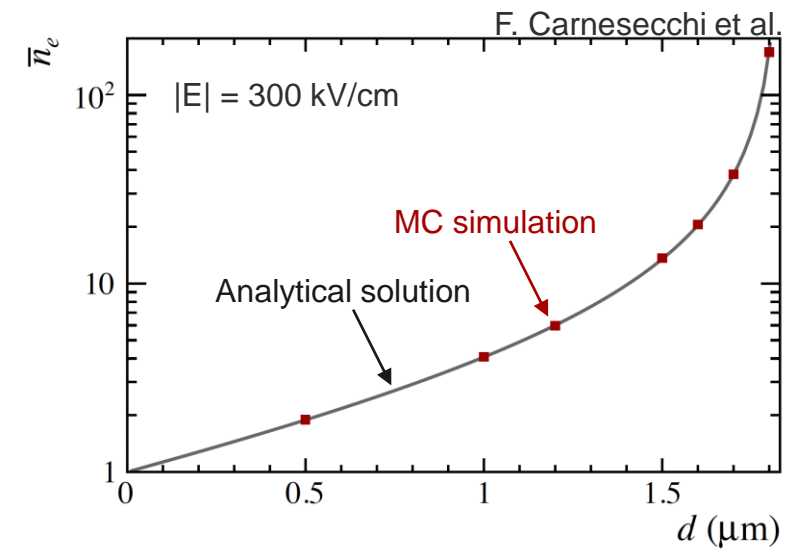
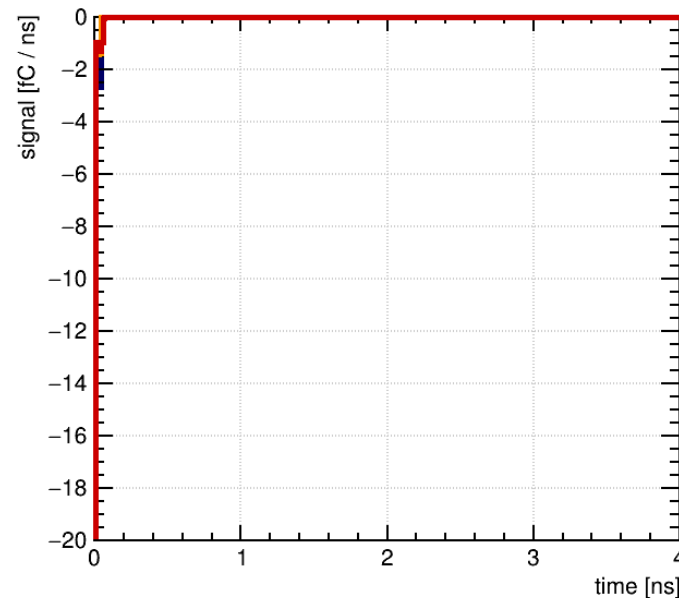
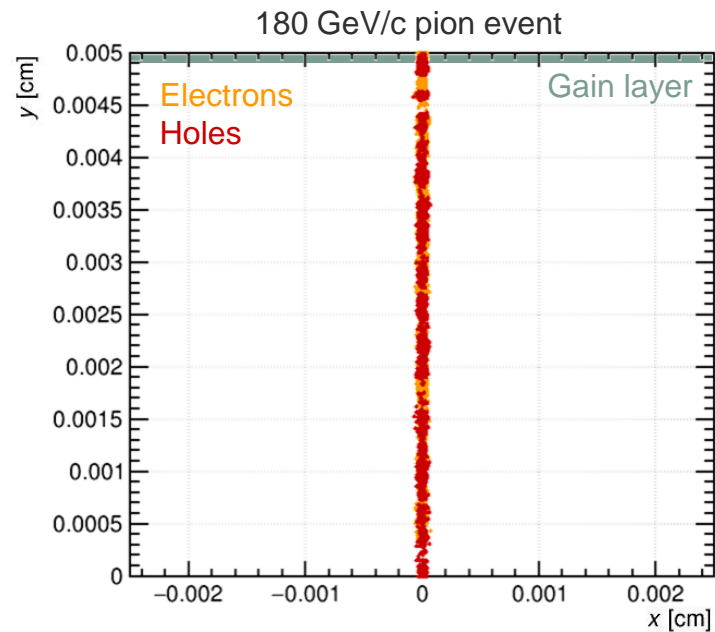
Garfield++ example: [https://gitlab.cern.ch/garfield/garfieldpp/-/tree/master/Examples/Silicon?ref\\_type=heads](https://gitlab.cern.ch/garfield/garfieldpp/-/tree/master/Examples/Silicon?ref_type=heads).



# Charge amplification (LGAD)

To simulate the development of an avalanche in high-field regions inside the sensor, such as a highly doped p+-type layer in an LGAD, one can:

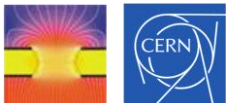
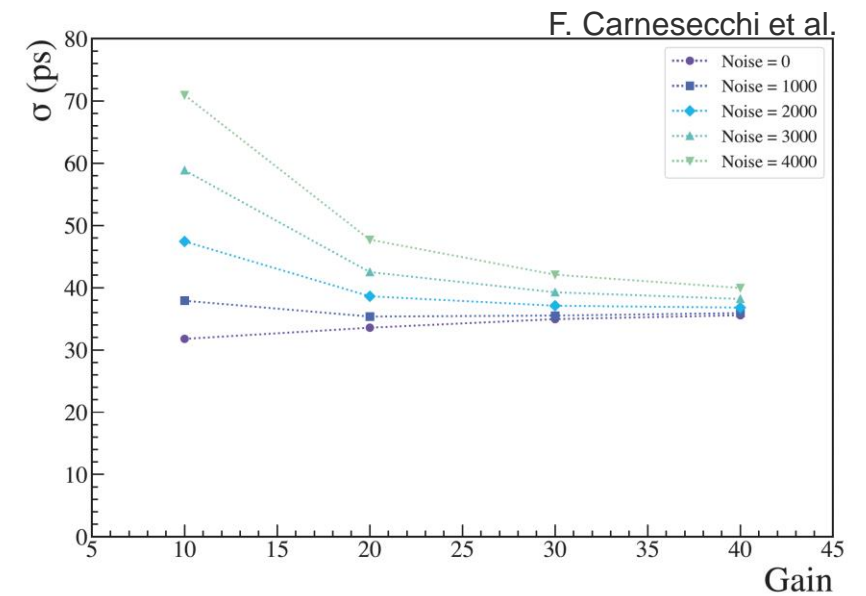
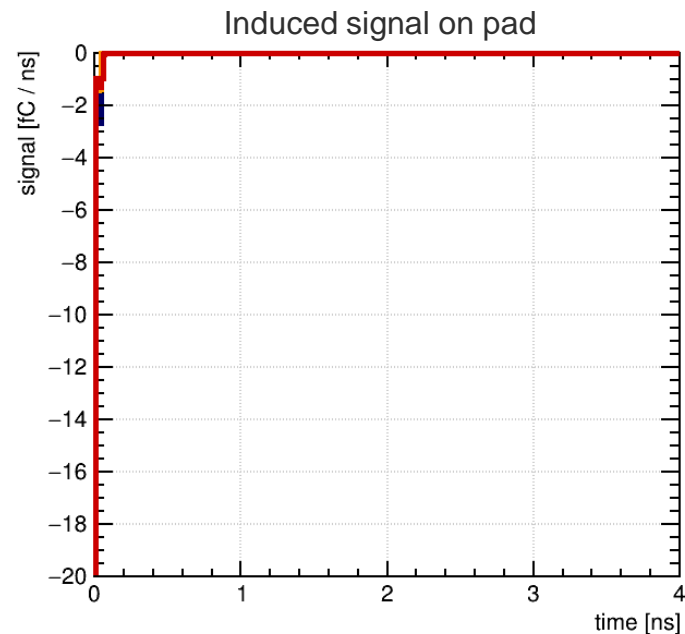
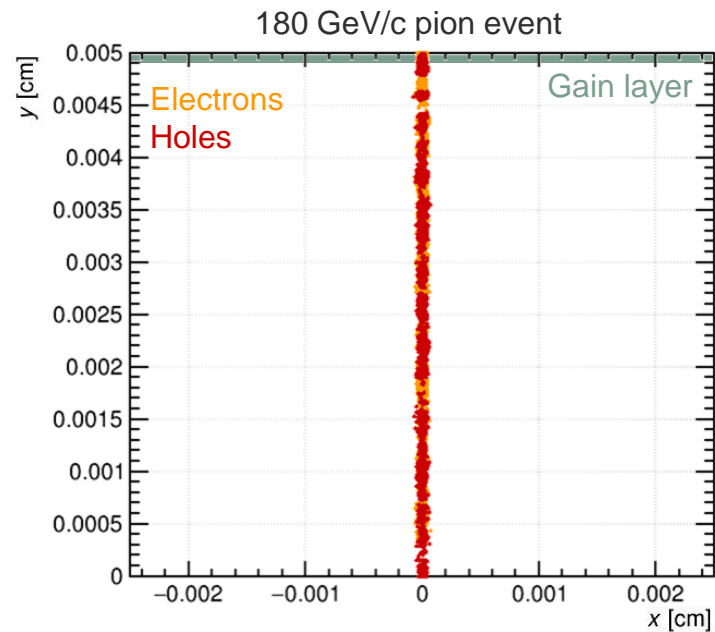
- Use the Van Overstraeten - de Man model (for impact ionisation coefficient silicon)
- import a map of transport data from TCAD



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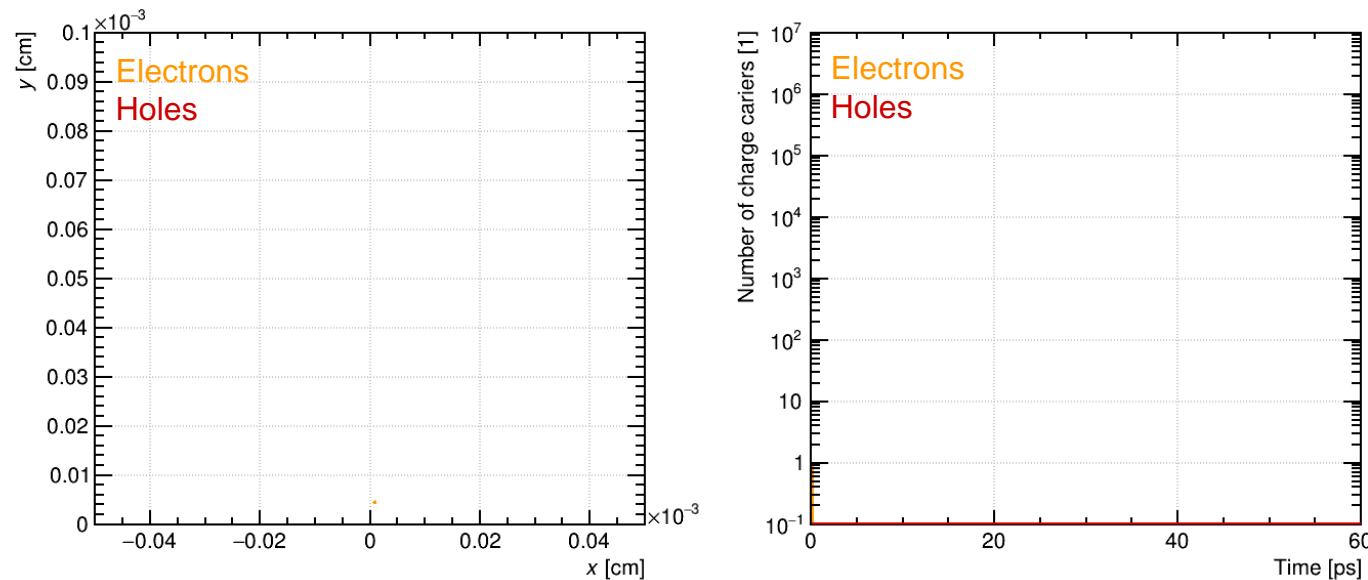


# Charge amplification (SPAD)

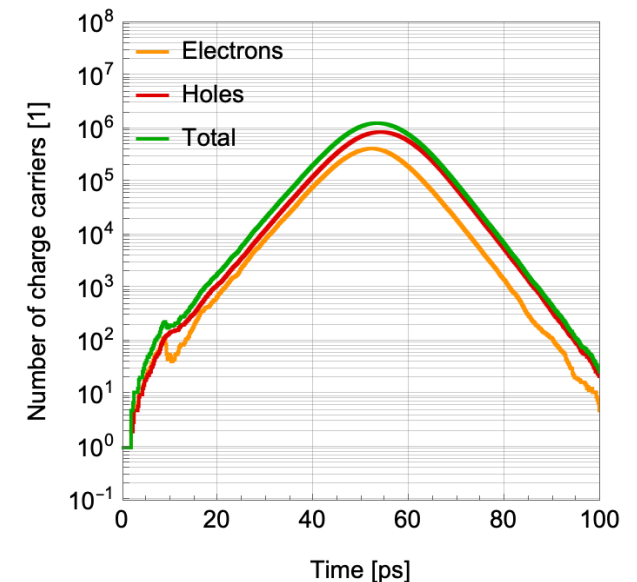
For SPADs Garfield++ can accurately capture the initial growth of the avalanche. However, there are two key mechanisms to describe the later-time dynamics:

- **Field reduction:** Due to bias voltage drop from the quenching resistor. Work in progress!
- **Space-Charge effects:** Due to electrons and holes causing time-dependent field modifications. Ongoing efforts in DRD1 WG4 for MPGDs and (M)RPCs.

Simulated avalanche without quenching

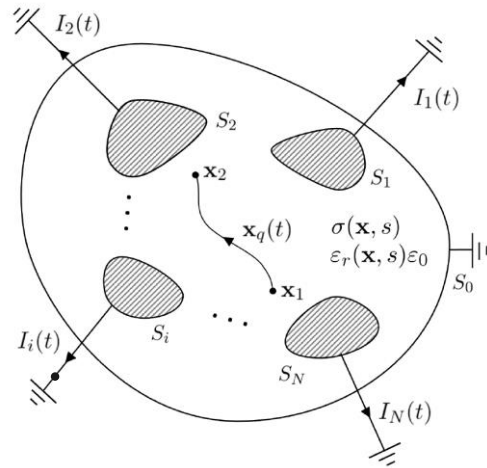


Simulated avalanche with quenching



# Ramo-Shockley theorem extension for conducting media

In detectors with resistive elements, signal timing depends on both charge movement in the drift medium and the time-dependent reaction of resistive materials.

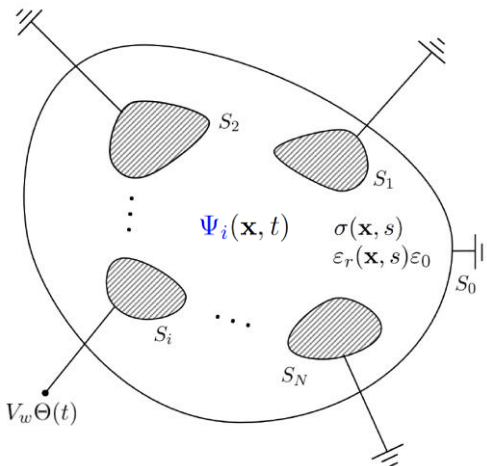


$$I_i(t) = -\frac{q}{V_w} \int_0^t \mathbf{H}_i [\mathbf{x}_q(t'), t - t'] \cdot \dot{\mathbf{x}}_q(t') dt'$$

$$\mathbf{H}_i(\mathbf{x}, t) := -\nabla \frac{\partial \Psi_i(\mathbf{x}, t) \Theta(t)}{\partial t}$$

The **dynamic weighting potential**  $\psi_i(\mathbf{x}, t)$  can be calculated:

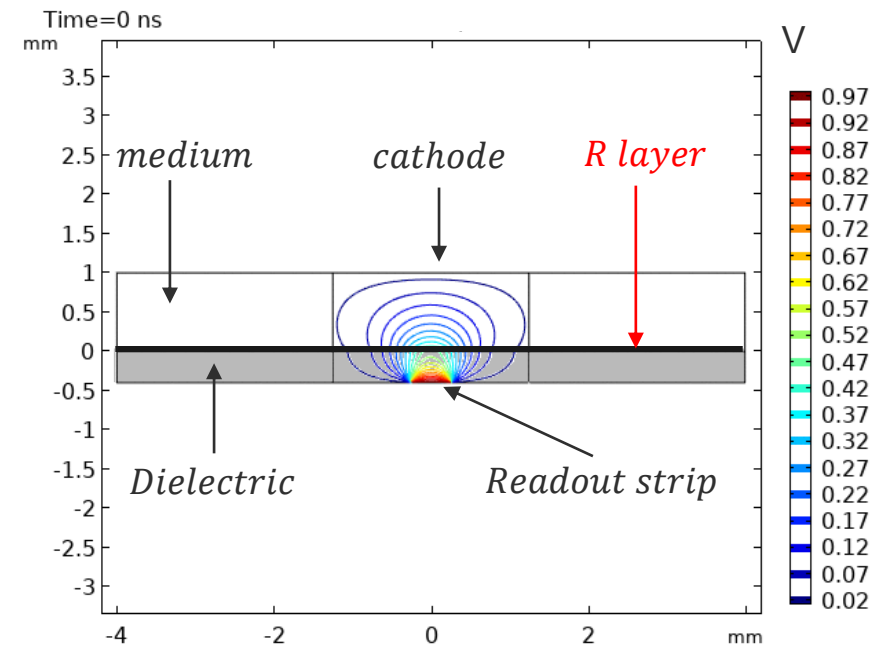
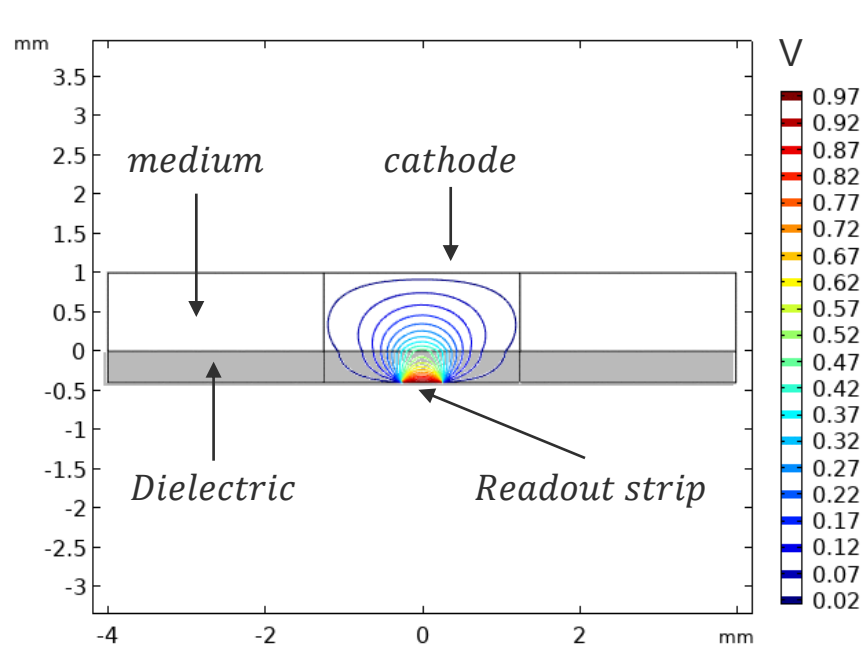
1. Remove the all the drifting charges.
2. Apply the biasing voltage  $V_b$  to obtain  $\psi_b(\mathbf{x})$ .
3. Apply an additional voltage pulls  $V_w \Theta(t)$  to the electrode at time  $t = 0$ , where  $V_w \ll V_b$ . The resulting potential is given by  $\psi(\mathbf{x}, t) = \psi_i(\mathbf{x}, t) + \psi_b(\mathbf{x})$ .
4. Obtaining the weighting potential is thus:  $\psi_i(\mathbf{x}, t) = \psi(\mathbf{x}, t) - \psi_b(\mathbf{x})$ .



# Ramo-Shockley theorem extension for conducting media

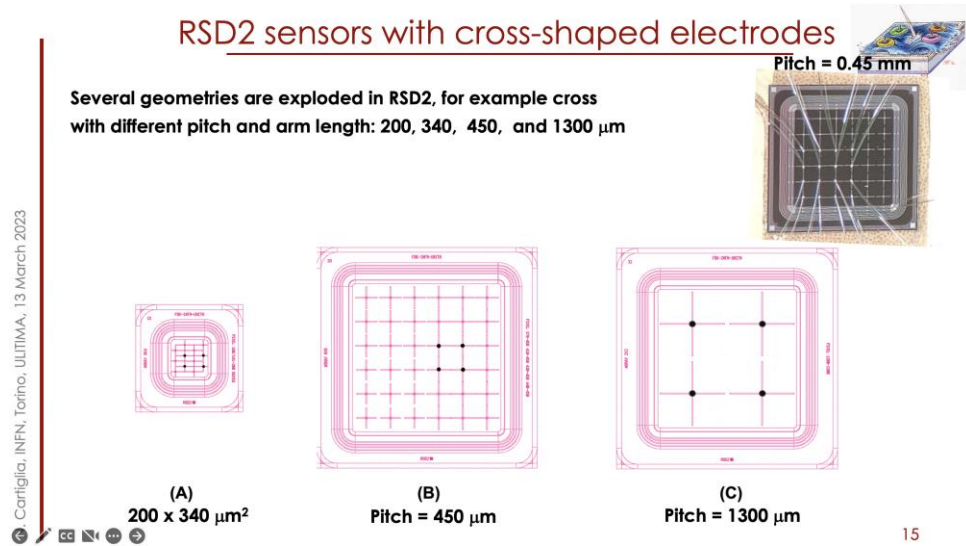
The time-dependent weighting potential captures signal dynamics from resistive elements. This can be obtained analytically for limited geometries; hence, a numerical approach was developed using FEM solvers:

- **COMSOL:** Implemented and verified against experimental data.
- **TCAD:** Implemented, but this still needs to be tested in more detail.



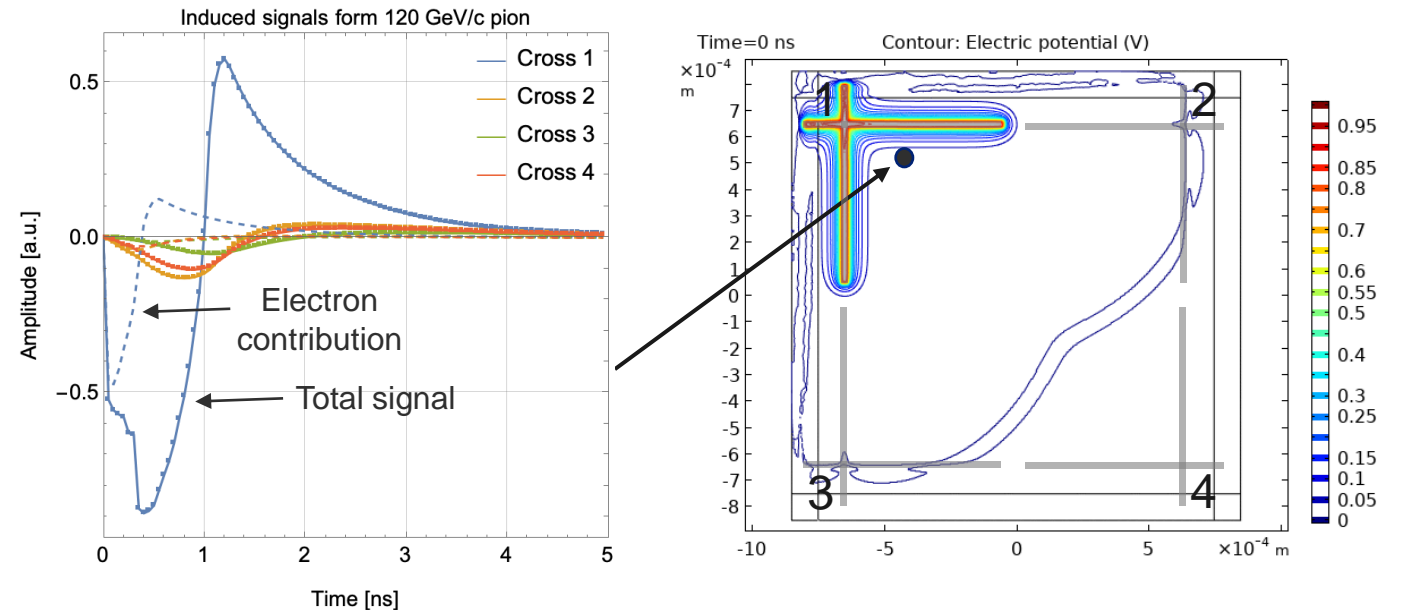
# AC-LGAD or Resistive Silicon Detector

Using COMSOL, the weighting potential of cross-shaped electrodes in a Resistive Silicon Detector (RSD) was calculated. This is passed to Garfield++ for the Monte Carlo simulation.



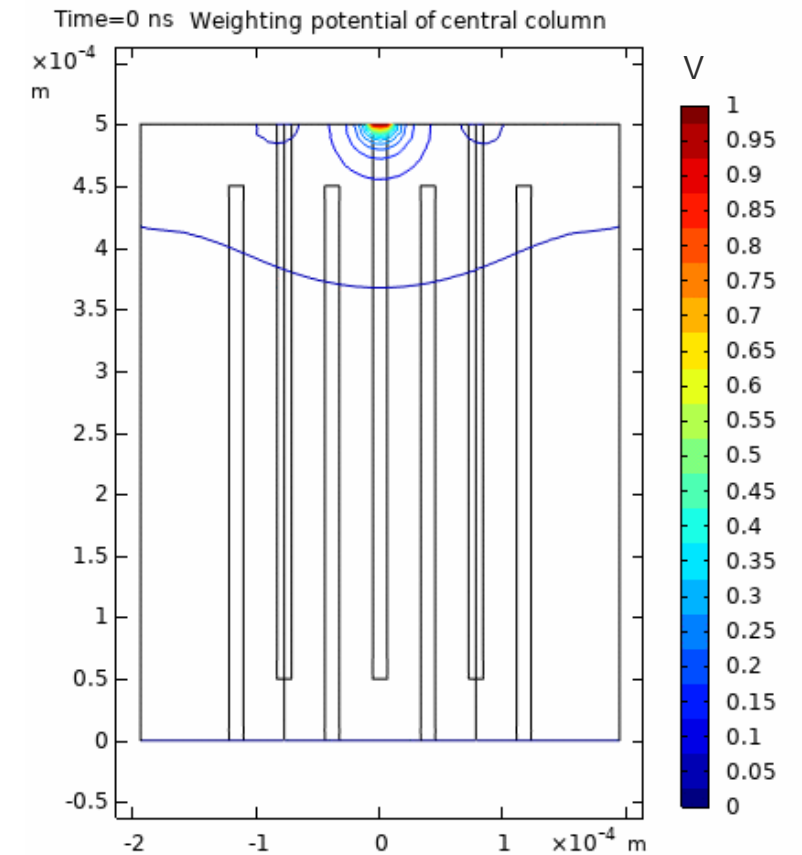
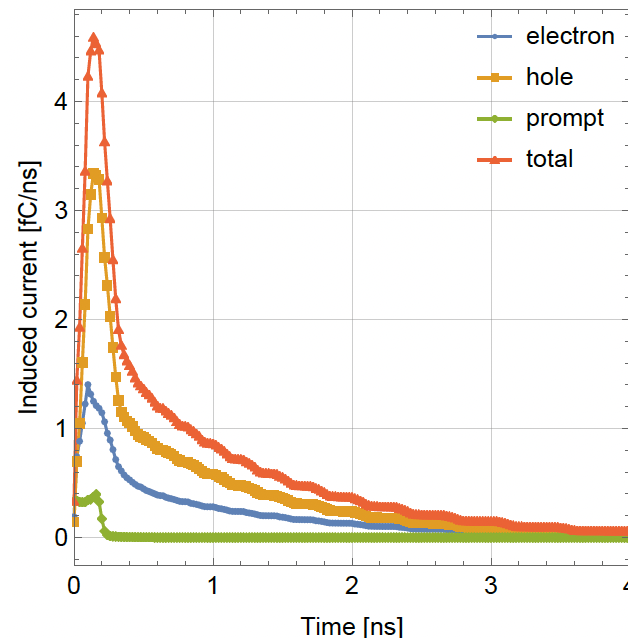
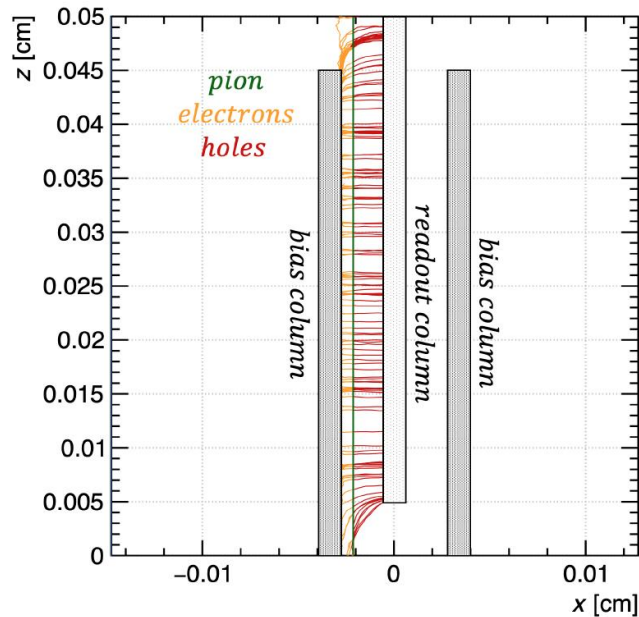
Slide borrowed from N. Cartiglia: [ULITIMA 2023](#).

Preliminary simulated response



# 3D Diamond sensor

In contrast to its silicon counterpart, the 3D electrode structure is achieved by inducing a local phase transition in the diamond, resulting in graphitic pillar electrodes that have a finite conductivity.



# Summary

Garfield++ is an object-oriented toolkit designed for detailed simulations of particle detectors, using ionization measurements in gases and semiconductors.

- **Primary interaction:** Interfaces with Heed to generate initial coordinates for electron-hole pairs from charged particles crossing the sensor.
- **Electric field setup:** Electric fields can be set using built-in functions or imported from FEM solvers, such as TCAD.
- **Drift and ionization simulation:** Includes built-in models for simulating drift lines and impact ionization for electrons and holes. Alternatively, relevant parameters can be sourced from TCAD.
- **Signal induction:** For sensors with regions of finite conductivity (e.g., AC-LGADs), the time-dependent weighting potential can be used for an accurate description of the signal induction process.

**Thank you for your attention!**

